

MCR218-2G, MCR218-4G, MCR218-6G



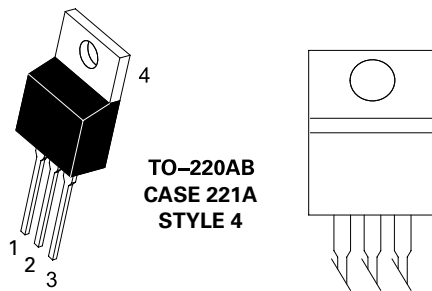
Description

Designed primarily for half-wave ac control applications, such as motor controls, heating controls and power supplies; or wherever half-wave silicon gate-controlled, solid-state devices are needed.

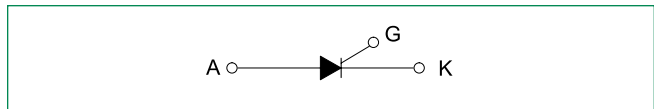
Features

- Glass-Passivated Junctions
- Blocking Voltage to 400 Volts
- TO-220 Construction – Low Thermal Resistance, High Heat Dissipation and Durability

Pin Out



Functional Diagram



Additional Information



Datasheet



Resources



Samples

Maximum Ratings ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Rating	Symbol	Value	Unit
Peak Repetitive Off-State Voltage (Note 1) (– 40 to 125°C, Sine Wave, 50 to 60 Hz, Gate Open)	V_{DRM}^* V_{RRM}	50	V
On-State RMS Current (180° Conduction Angles; $T_C = 85^\circ\text{C}$)	$I_{TM(RMS)}$	12	A
Peak Discharge Current (Note 2)	I_{TM}	300	A
Average On-State Current (180° Conduction Angles; $T_C = 85^\circ\text{C}$)	$I_{T(AV)}$	8.0	A
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, $T_J = 125^\circ\text{C}$)	I_{TSM}	100	A
Circuit Fusing Consideration ($t = 8.3$ ms)	I^2t	40	A ² sec
Forward Peak Gate Current (Pulse Width ≤ 1.0 μsec , $T_C = 80^\circ\text{C}$)	I_{GM}	2.0	A
Forward Peak Gate Current (Pulse Width ≤ 1.0 μsec , $T_C = 85^\circ\text{C}$)	I_{GM}	20	W
Forward Average Gate Power ($t = 8.3$ ms, $T_C = 85^\circ\text{C}$)	$P_{G(AV)}$	0.5	W
Operating Junction Temperature Range	T_J	-40 to +125	°C
Storage Temperature Range	T_{stg}	-40 to +150	°C
Mounting Torque	–	8.0	in. lb.

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

- V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.
- Ratings apply for $tw = 1$ ms. See Figure 1 for I_{TM} capability for various duration of an exponentially decaying current waveform, tw is defined as 5 time constants of an exponentially decaying current pulse.

Thermal Characteristics

Rating	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (AC) Junction-to-Ambient	$R_{\theta JC}$ $R_{\theta JA}$	2.0 60	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	T_L	260	°C

Electrical Characteristics - OFF ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Peak Repetitive Forward or Reverse Blocking Current ($V_D = \text{Rated } V_{DRM}$ and V_{RRM} ; Gate Open)	I_{DRM}^* I_{RRM}	-	-	10	mA
		-	-	2.0	

Electrical Characteristics - ON ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Peak Forward On-State Voltage (Note 2) ($I_{TM} = 32$ A) ($I_{TM} = 24$ A) (Note 3) ($I_{TM} = 300$ A, $tw = 1$ ms) (Note 4)	V_{TM}	–	– 6.0	2.2 –	V
Gate Trigger Current (Continuous dc) ($V_D = 12$ V; $R_L = 100$ Ω)	I_{GT}	2.0	7.0	30	mA
Gate Trigger Voltage (Continuous dc) ($V_D = 12$ V; $R_L = 100$ Ω)	V_{GT}	–	0.65	1.5	V
Gate Trigger Non-Current (Continuous dc) ($V_D = 12$ V; $R_L = 100$ Ω)	V_{GD}	0.2	0.40	–	V
Holding Current ($V_D = 12$ V, Initiating Current = 200 mA, Gate Open)	I_H	3.0	15	50	mA
Latch Current ($V_D = 12$ V, $I_G = 30$ mA)	I_L	–	35	80	mA
Gate Controlled Turn-On Time (Note 5) ($V_D = \text{Rated } V_{DRM}$, $I_G = 150$ mA) ($I_{TM} = 24$ A Peak)	V_{GT}	–	1.0	–	μs

Dynamic Characteristics

Characteristic	Symbol	Min	Typ	Max	Unit
Critical Rate of Rise of Off-State Voltage ($V_D = \text{Rated } V_{DRM}$, Exponential Waveform, Gate Open, $T_J = 125^\circ\text{C}$)	dv/dt	10	–	–	V/ μs
Critical Rate of Rise of On-State Current $I_G = 150 \text{ A}$ $T_J = 125^\circ\text{C}$	di/dt	–	–	75	A/ μs

- Pulse duration $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- Ratings apply for $t_w = 1 \text{ ms}$. See Figure 1 for I_{TM} capability for various durations of an exponentially decaying current waveform. t_w is defined as 5 time constants of an exponentially decaying current pulse.
- The gate controlled turn-on time in a crowbar circuit will be influenced by the circuit inductance.

Voltage Current Characteristic of SCR

Symbol	Parameter
V_{DRM}	Peak Repetitive Forward Off State Voltage
I_{DRM}	Peak Forward Blocking Current
V_{RRM}	Peak Repetitive Reverse Off State Voltage
I_{RRM}	Peak Reverse Blocking Current
V_{TM}	Maximum On State Voltage
I_H	Holding Current

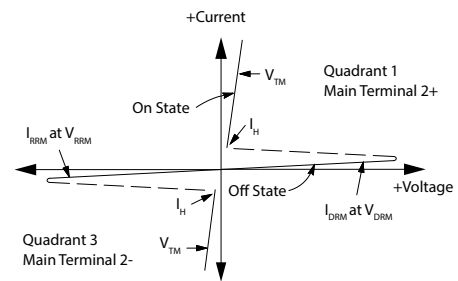


Figure 1. Current Derating

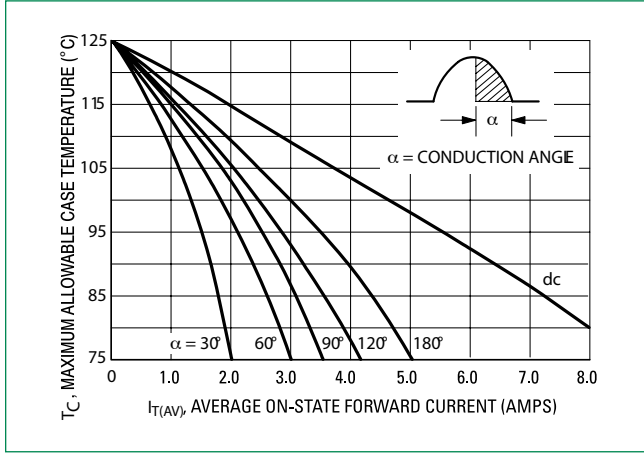


Figure 2. On-State Power Dissipation

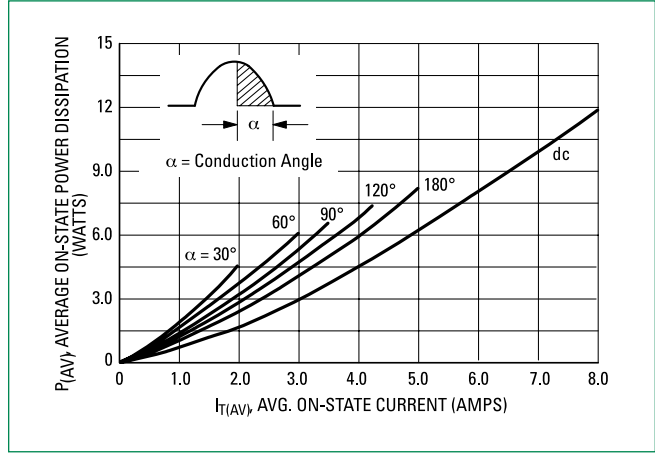


Figure 3. Typical Gate Trigger Current vs Temperature

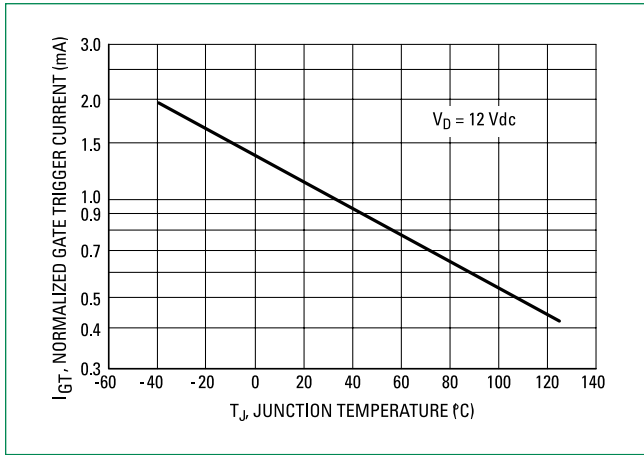


Figure 4. Typical Gate Trigger Voltage vs Temperature

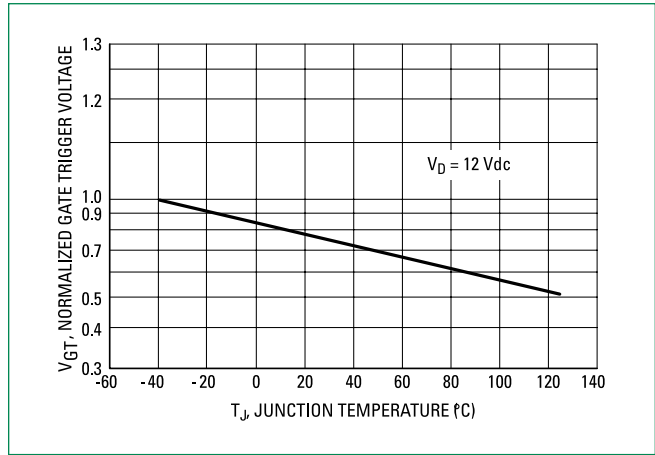


Figure 5. Typical Holding Current vs Temperature

